

Statistics Behind Error Analysis

TIPL 4201
TI Precision Labs – ADCs

Created by Art Kay

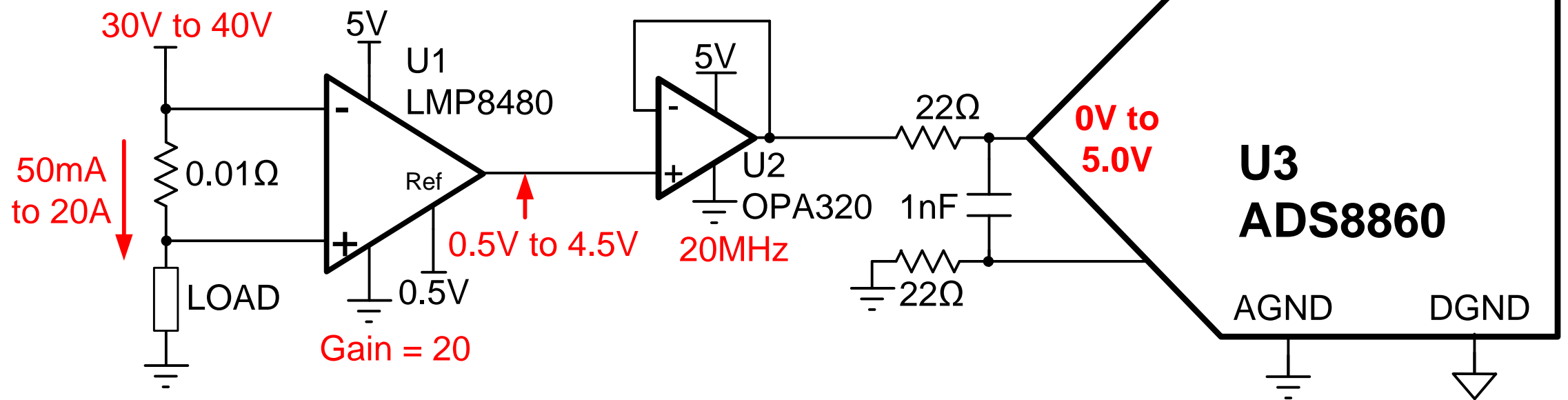
Presented by Peggy Liska

Find the worst case offset

Device	PARAMETER	MIN	TYP	MAX	UNITS
LMP8481	V_{OS} Offset Error	-265	± 80	+265	μV
OPA320	V_{OS} Offset Error	-150	± 40	+150	μV
ADS8860	E_O Offset Error	-4	± 1	+4	mV

Worst case offset at ADS Input
$V_{osT} = Gain \cdot V_{U1} + V_{U2} + V_{U3}$
$V_{osT} = 20 \cdot (265\mu V) + (150\mu V) + (4mV)$
$V_{osT} = 9.27mV$

This result may be statistically unrealistic



Statistics Behind Typical and Maximum

PARAMETER ADS8860		MIN	TYP	MAX	UNITS
E_O	Offset Error	-4	± 1	+4	mV
E_G	Gain Error	-0.01	± 0.005	+0.01	%FSR

Gaussian Distribution

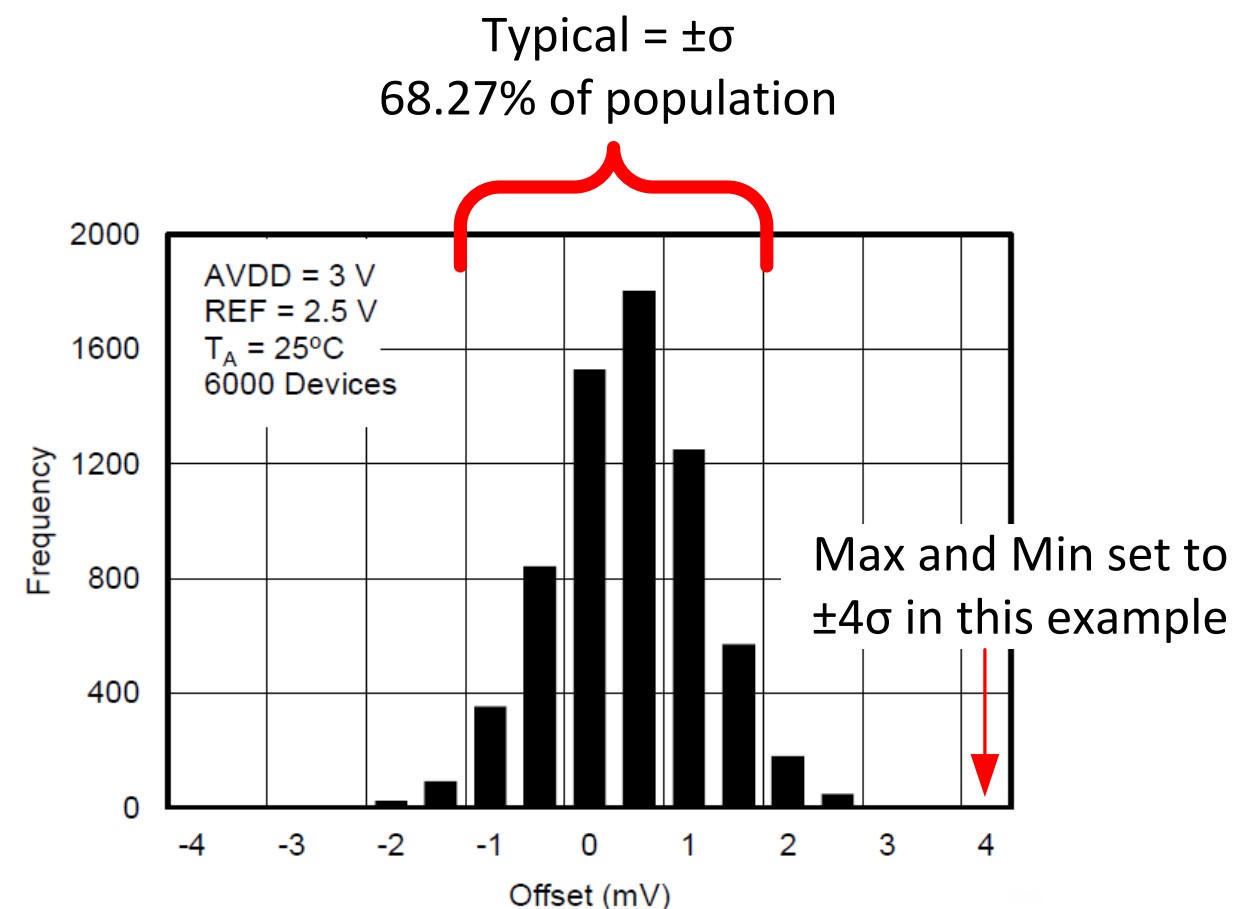
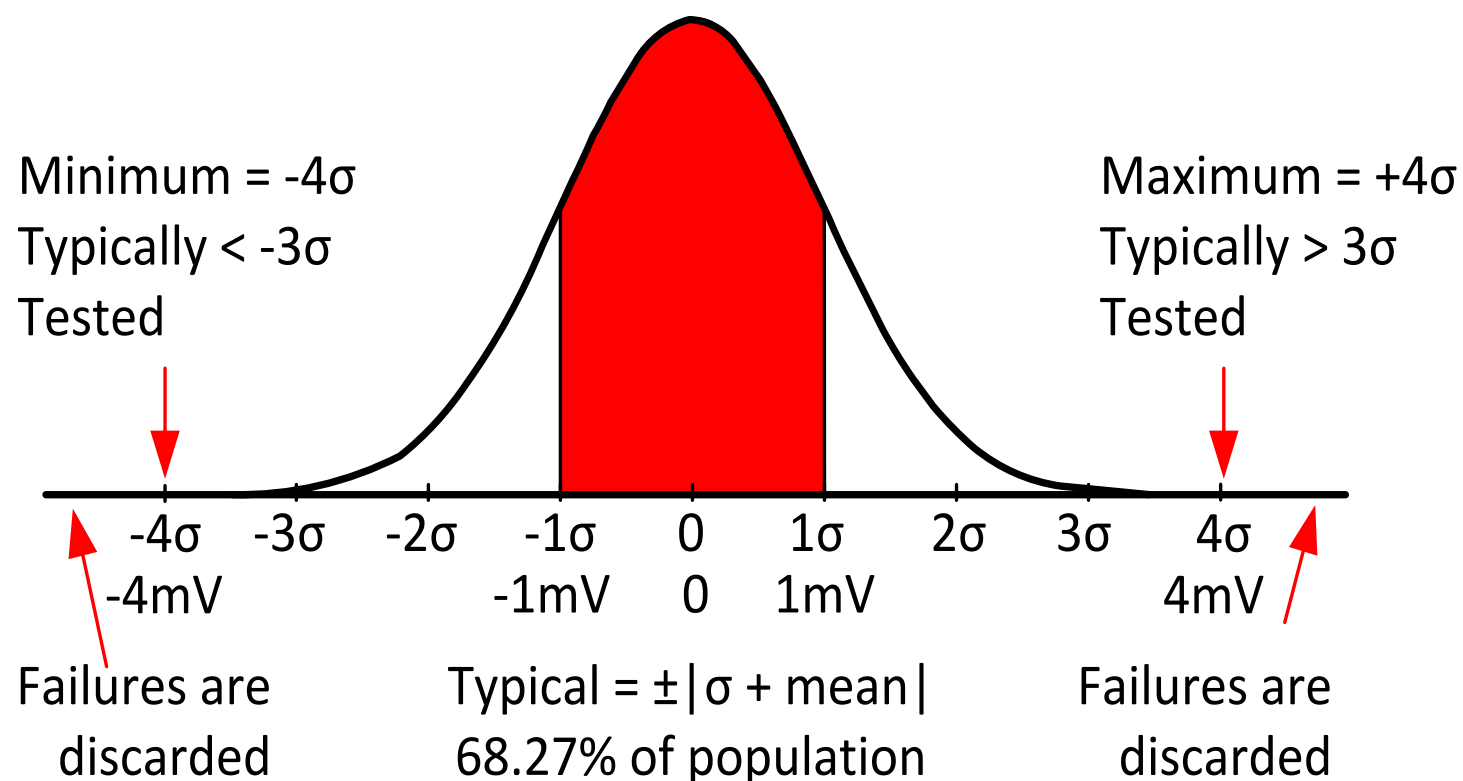


Figure 41. TYPICAL DISTRIBUTION OF OFFSET ERROR

Probability that we are near worst case

PARAMETER ADS8860	MIN	TYP	MAX	UNITS
E_O Offset Error	-4	± 1	+4	mV
E_G Gain Error	-0.01	± 0.005	+0.01	%FSR

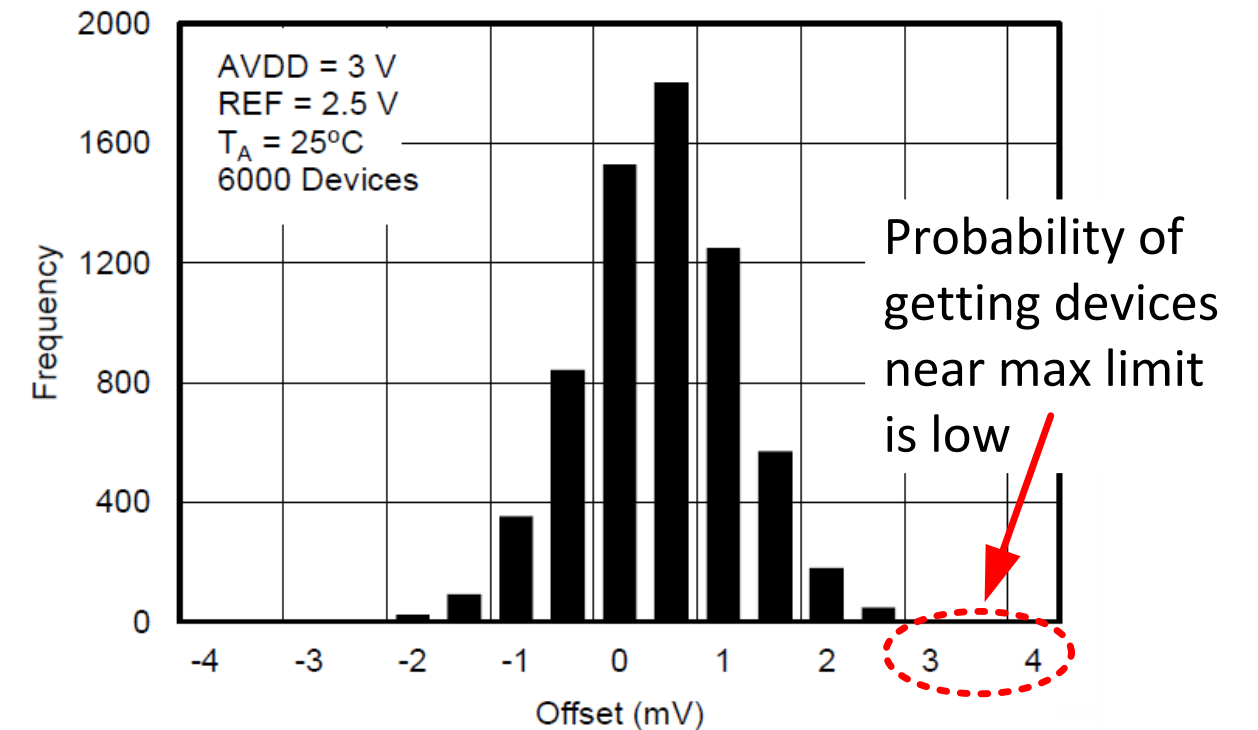
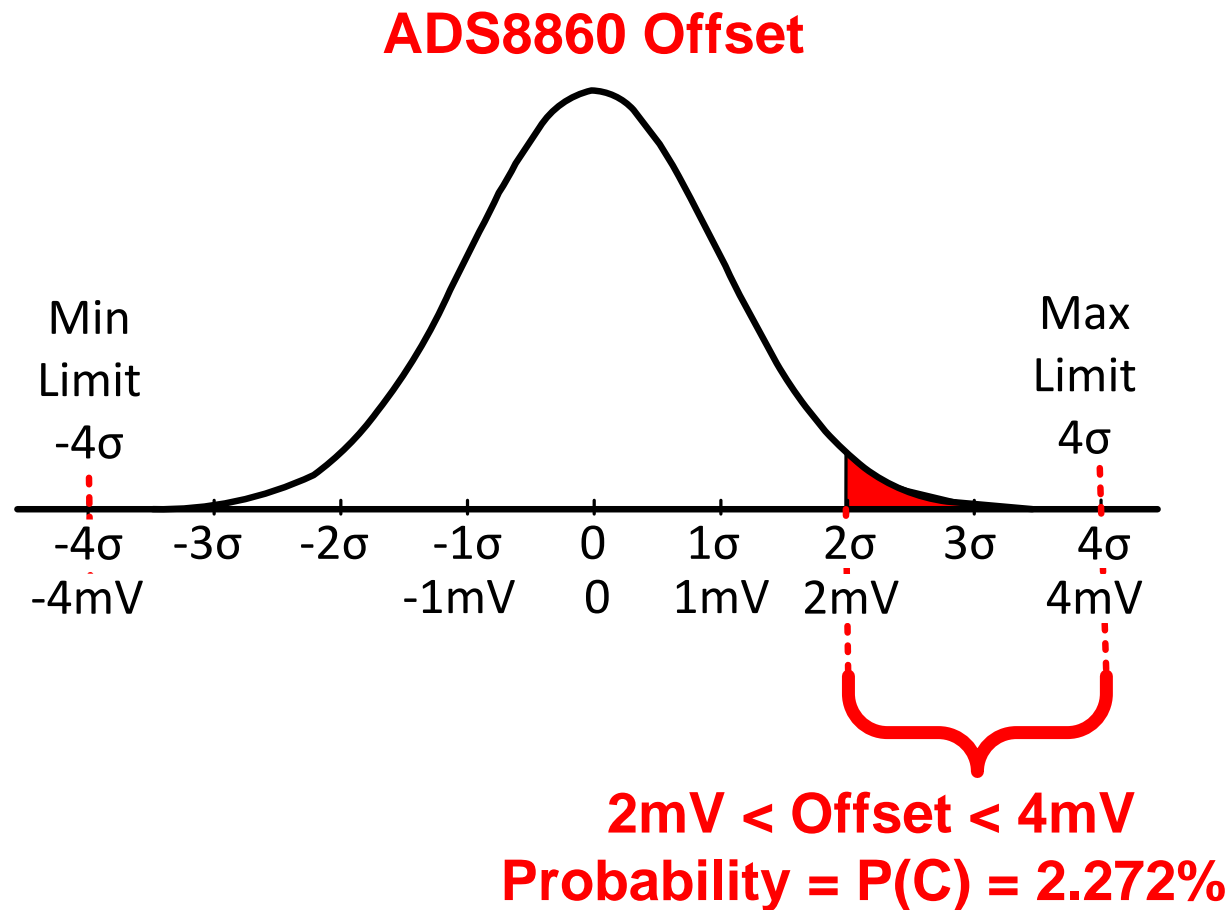
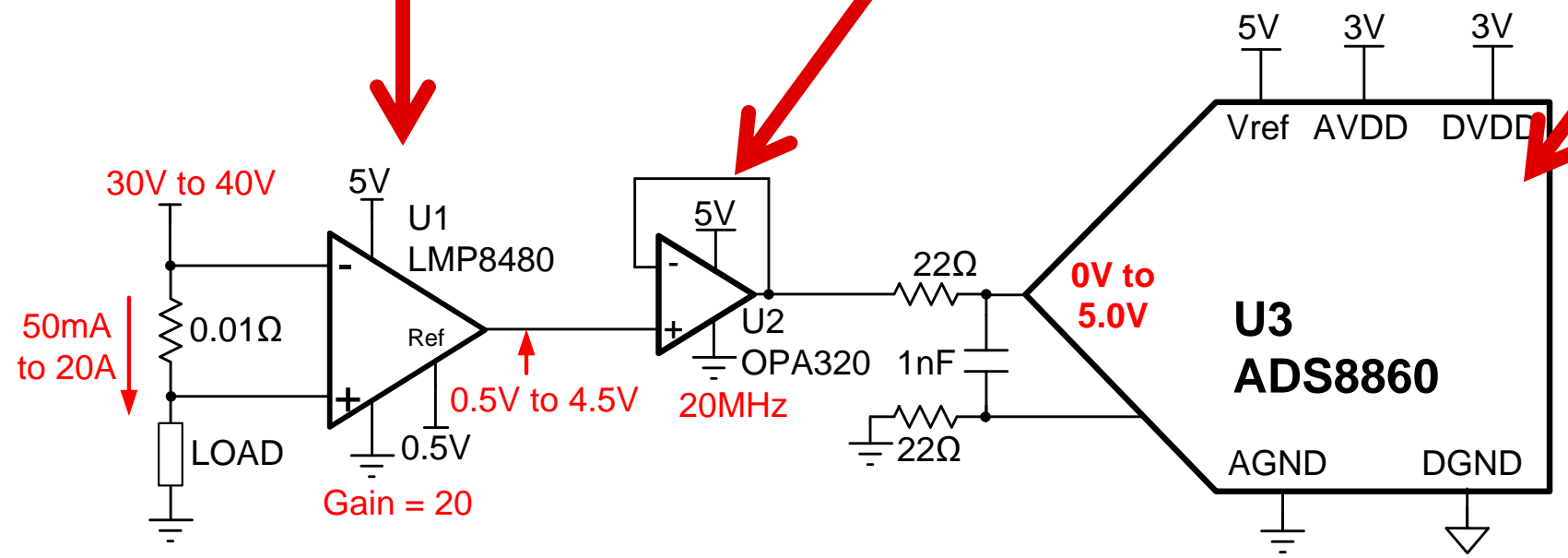
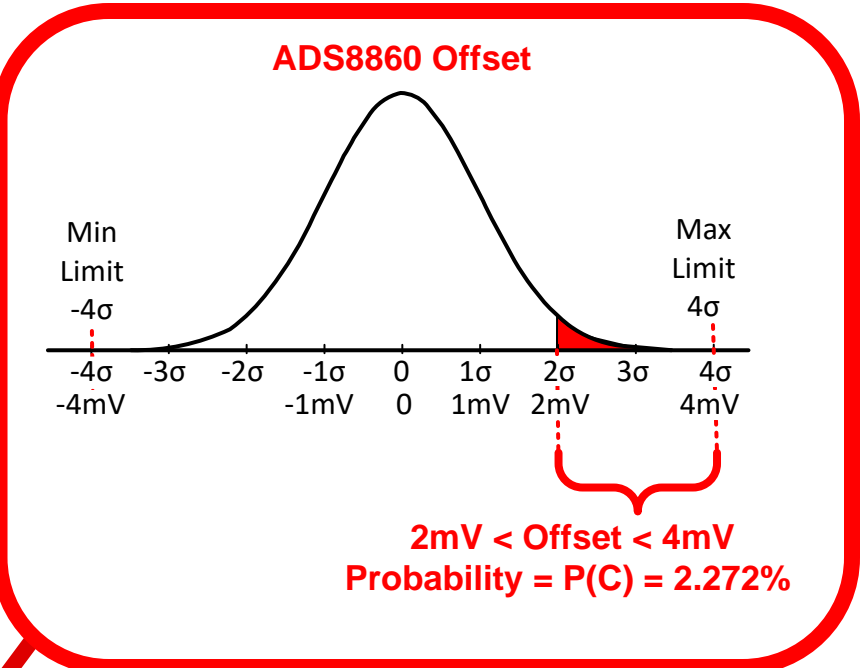
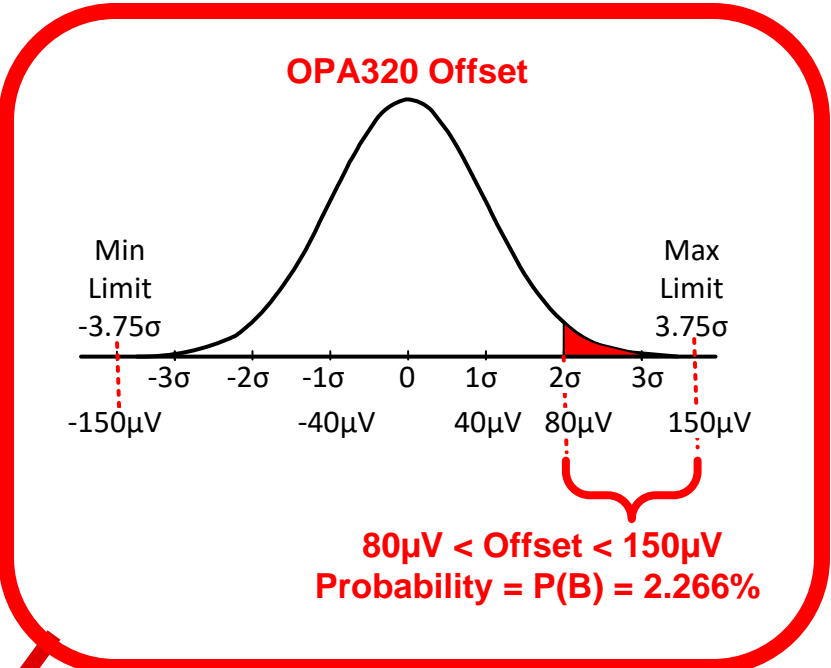
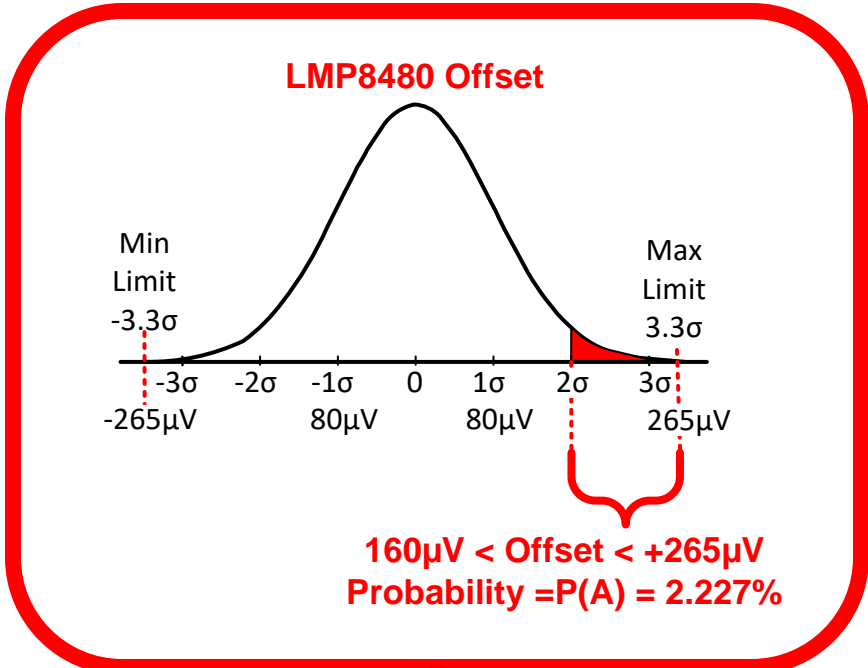


Figure 41. TYPICAL DISTRIBUTION OF OFFSET ERROR

Compounding probabilities “near” worst case



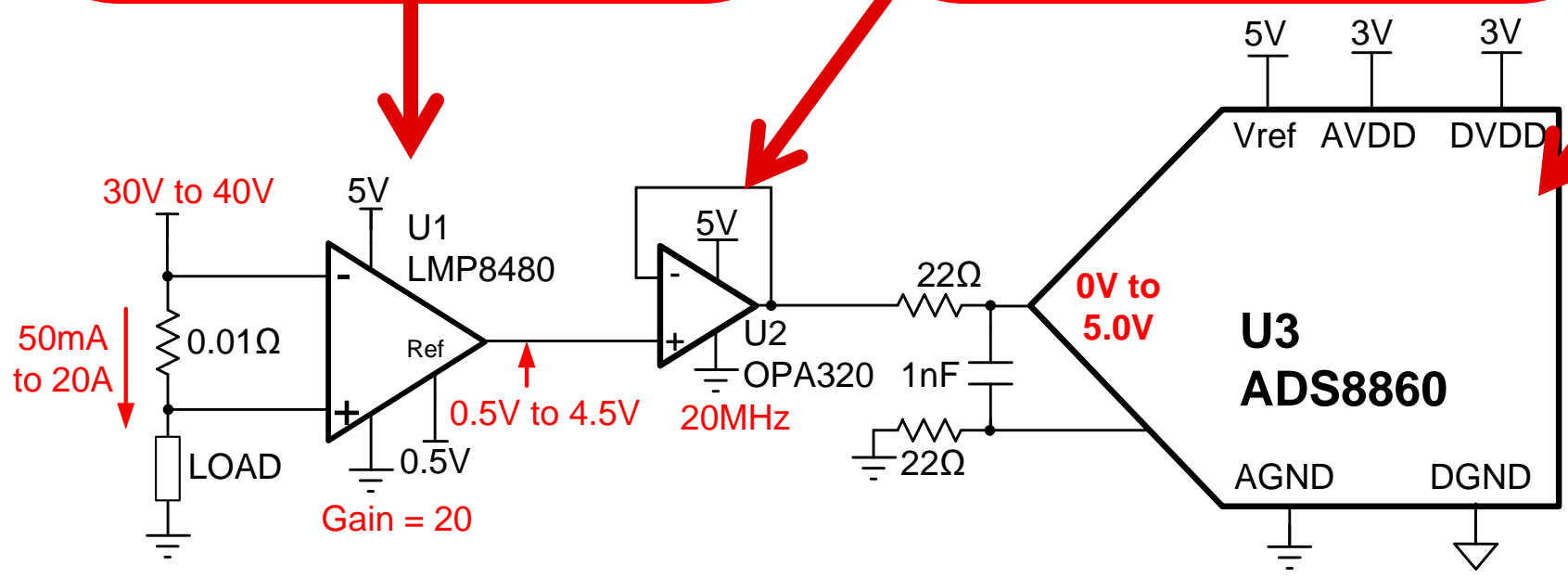
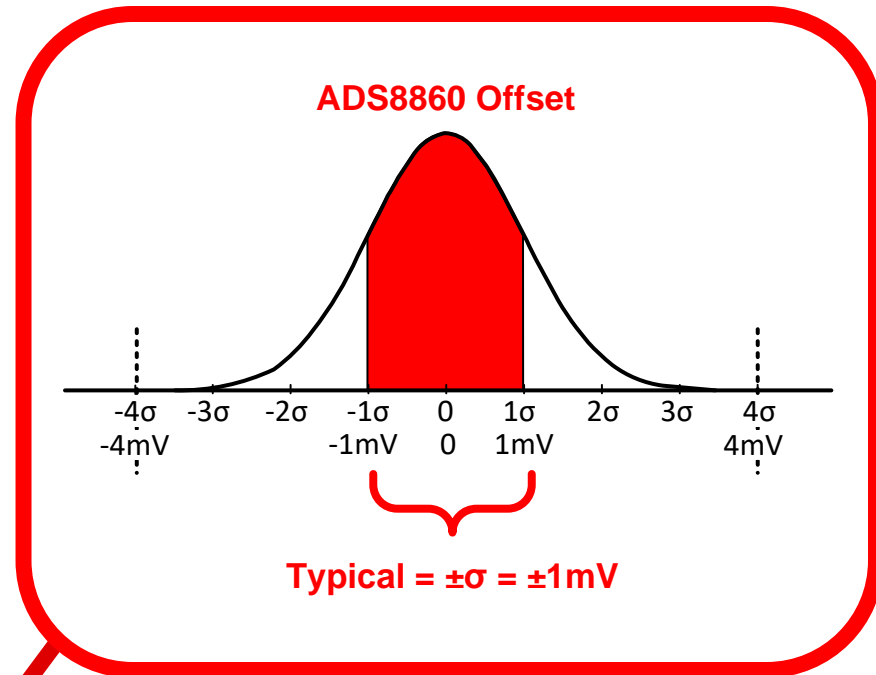
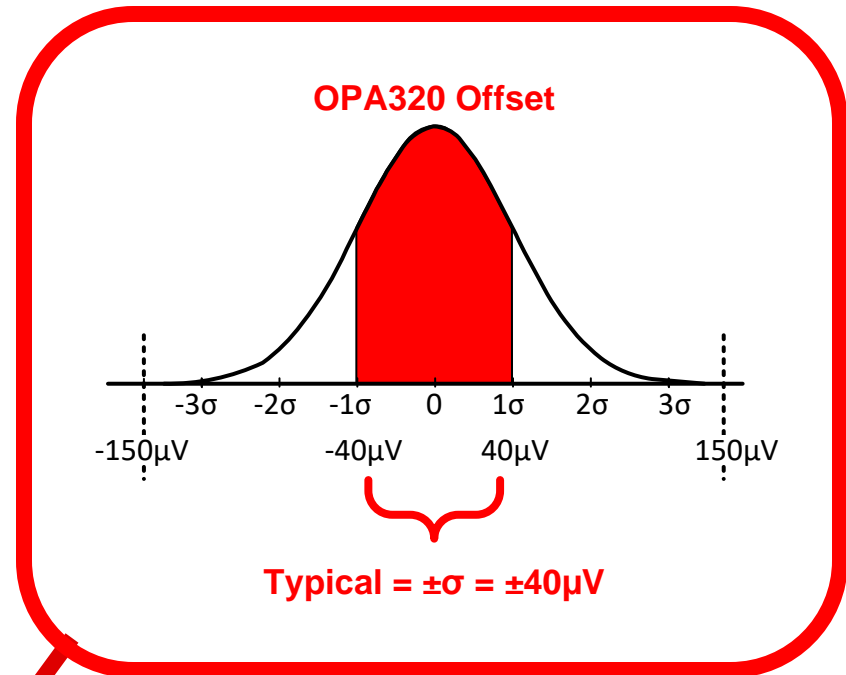
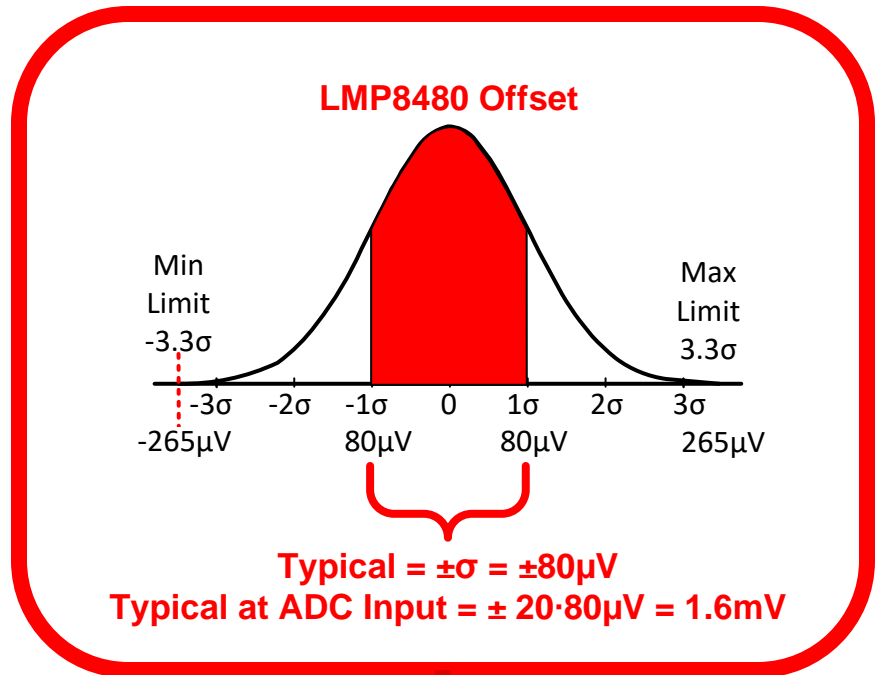
The probability that all three offsets are near worst case

$$P = P(A) \cdot P(B) \cdot P(C)$$

$$P = (0.02227)(0.02266)(0.02272)$$

$$\%P = 100 \cdot P = 0.0011\%$$

A more practical approach: use the typical limit



Typical offset at ADC Input

$$V_{osT} = \sqrt{(20 \cdot V_{osINA})^2 + (V_{osOPA})^2 + (V_{osADS})^2}$$

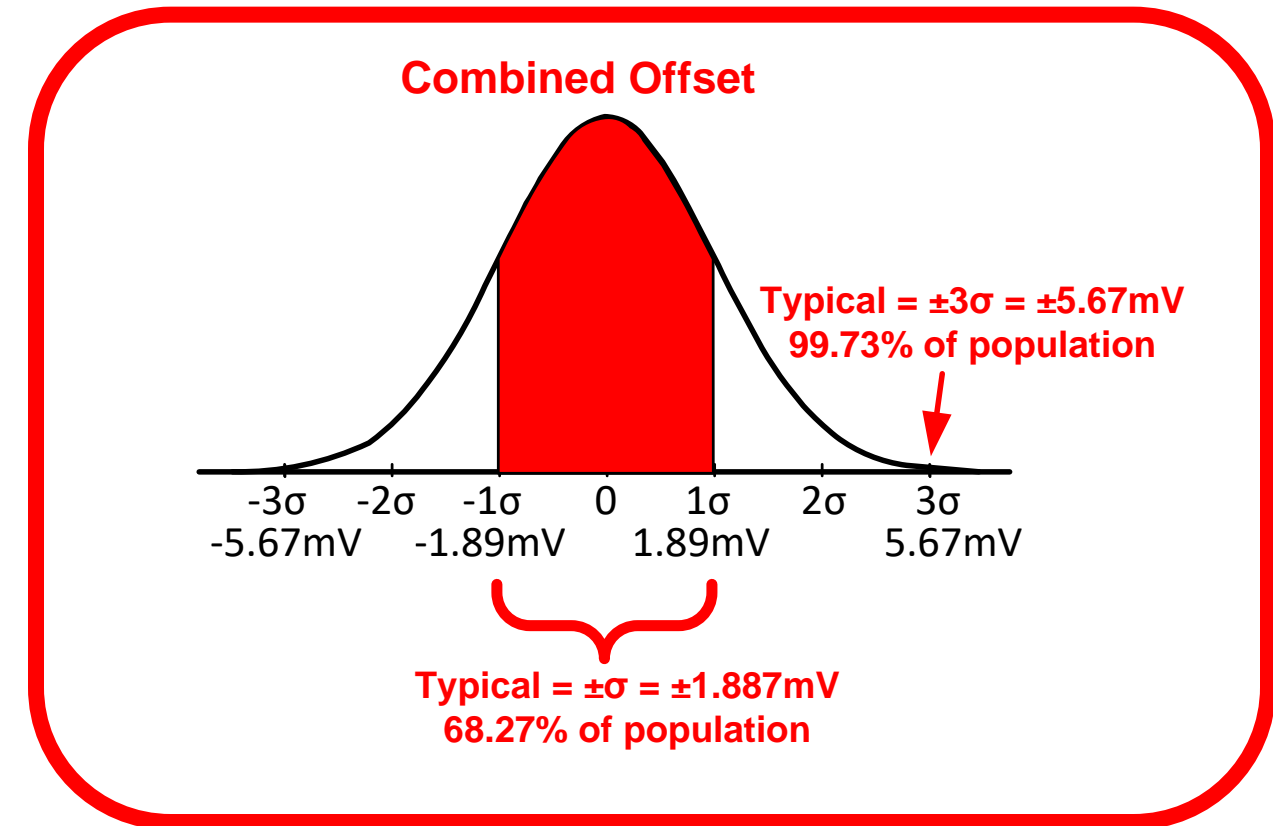
$$V_{osT} = \sqrt{(20 \cdot 80\mu\text{V})^2 + (40\mu\text{V})^2 + (1\text{mV})^2}$$

$$V_{osT} = 1.887\text{mV}$$

A more practical approach: use typical

Number of Standard deviations	Probability Inside limit	Probability Outside limit
$\pm 1 \cdot \sigma$	68.27%	31.73%
$\pm 2 \cdot \sigma$	95.45%	4.55%
$\pm 3 \cdot \sigma$	99.73%	0.27%
$\pm 4 \cdot \sigma$	99.9937%	0.0063%
$\pm 5 \cdot \sigma$	99.99994%	$5.73 \cdot 10^{-5} \%$
$\pm 6 \cdot \sigma$	$\approx 100\%$	$1.97 \cdot 10^{-7} \%$

Set end system specifications based on risk tolerance



Typical offset at ADC Input

$$V_{osT} = \sqrt{(20 \cdot V_{osINA})^2 + (V_{osOPA})^2 + (V_{osADS})^2}$$

$$V_{osT} = \sqrt{(20 \cdot 80\mu V)^2 + (40\mu V)^2 + (1mV)^2}$$

$$V_{osT} = 1.887mV$$

Thanks for your time!
Please try the quiz.

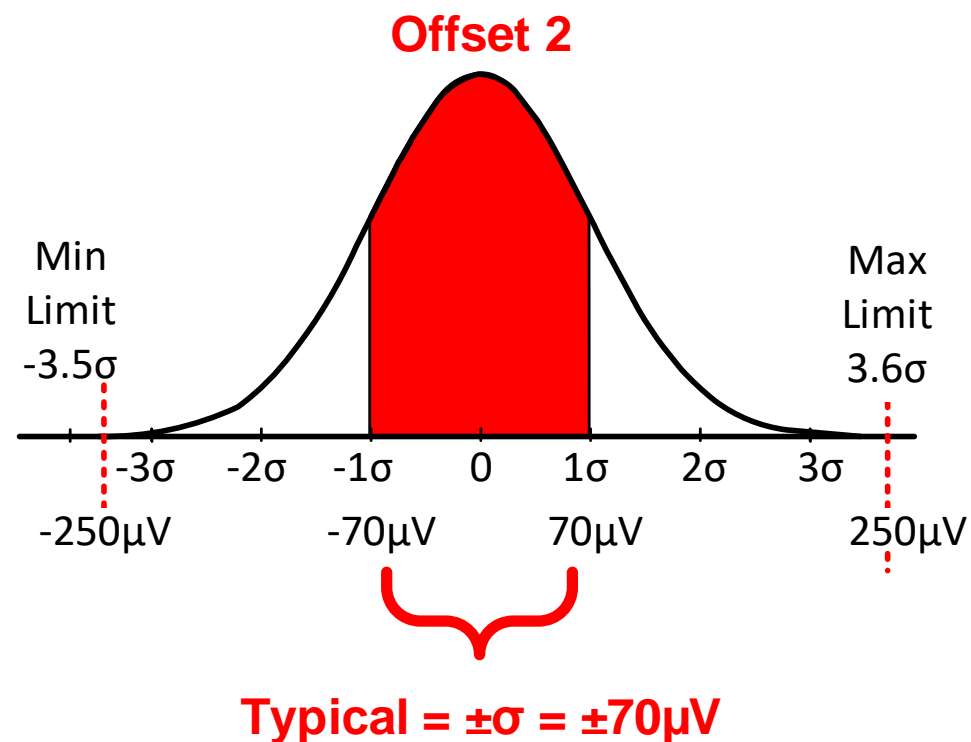
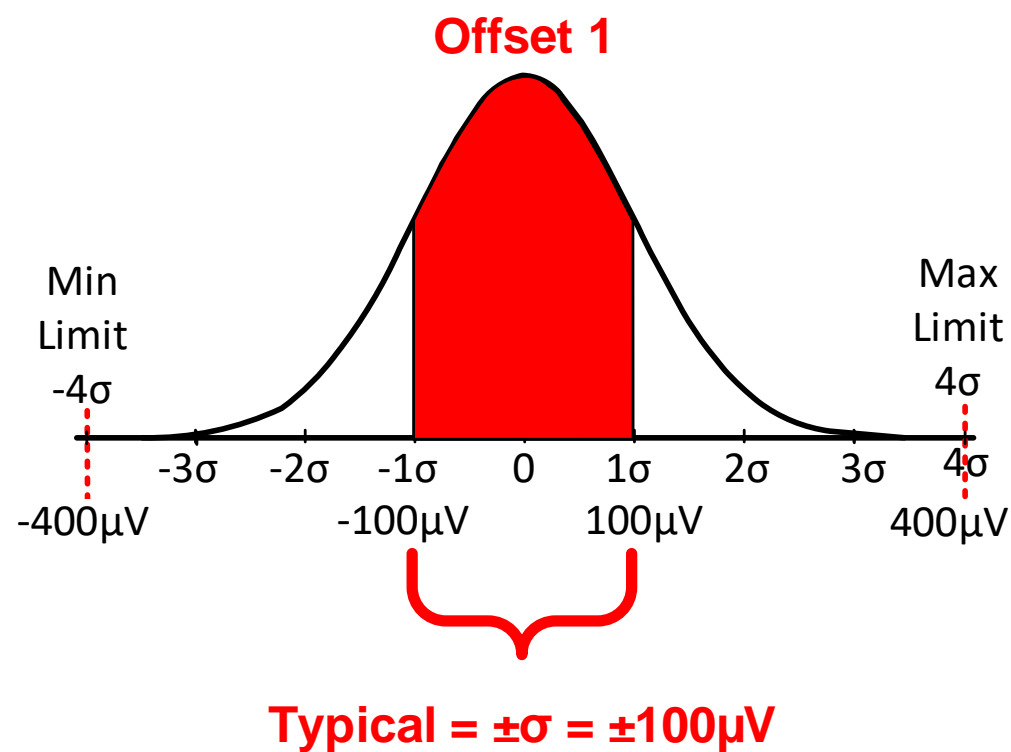
Quiz: Statistics Behind Error Analysis

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Quiz: Statistics Behind Error Analysis

1. The two uncorrelated Gaussian distributions below are being added. Draw the graph for the sum of the two distributions.



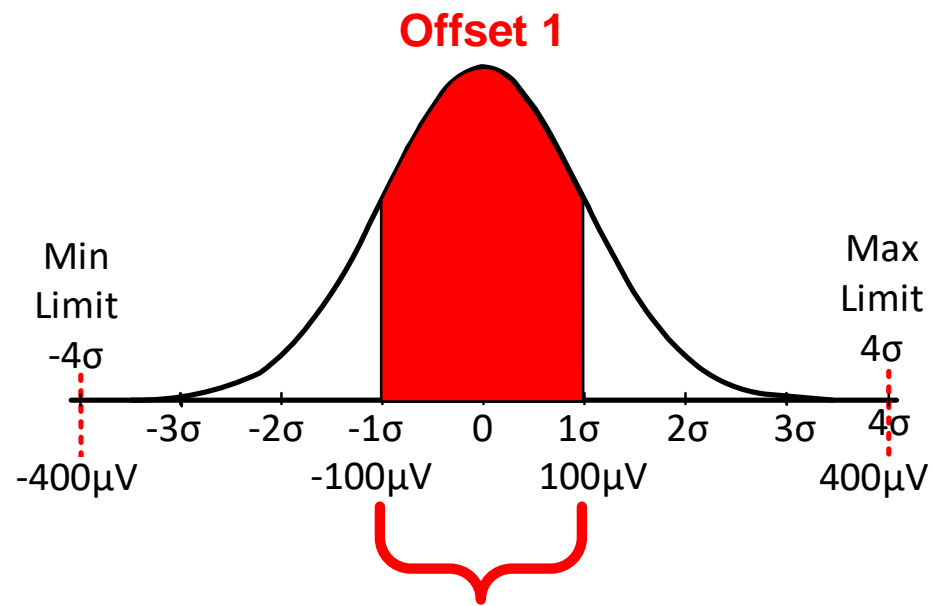
Quiz: Statistics Behind Error Analysis

2. What is the statistical significance of the typical offset specification?
- a) The typical offset specification is the mean offset.
 - b) The typical is the mean plus one standard deviation. However, typically the mean is near zero so typical can be approximated as one standard deviation.
 - c) The typical is tested and any device that exceeds the typical value is discarded.
 - d) 99.7% of devices will be inside the typical limit.
3. When combining error sources A and B, they should be added _____.
- a. Directly (Total Error = A + B).
 - b. Using Simpson's rule
 - c. Using the Adaptive Runge-Kutta Method
 - d. As the square root sum of the squares ($Total\ Error = \sqrt{A^2 + B^2}$)

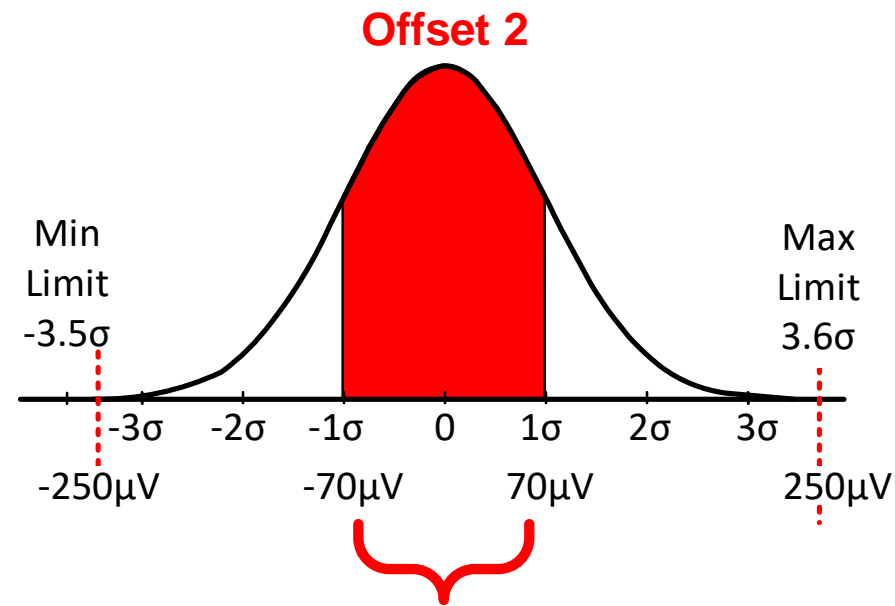
Solutions

Quiz: Statistics Behind Error Analysis

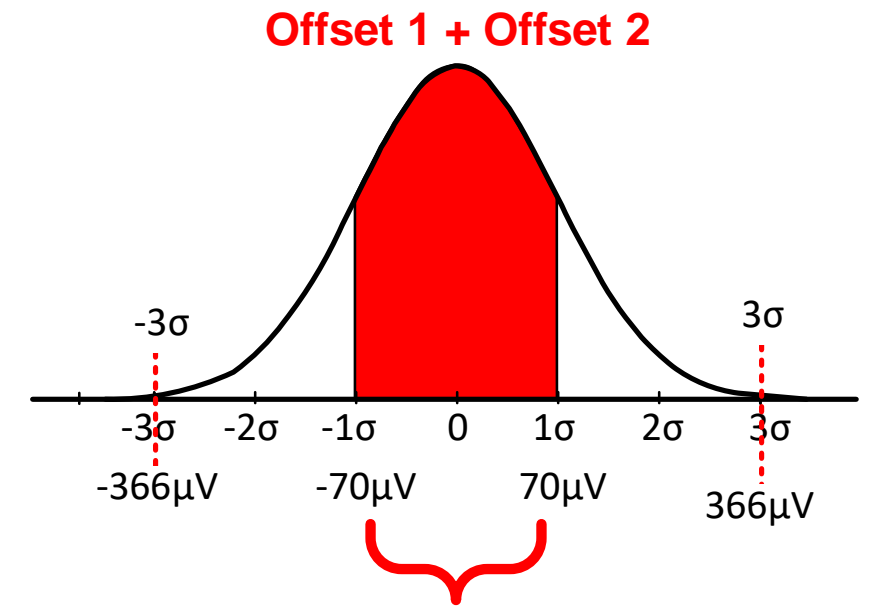
1. The two uncorrelated Gaussian distributions below are being added. Draw the graph for the sum of the two distributions.



Typical = $\pm\sigma = \pm 100\mu\text{V}$



Typical = $\pm\sigma = \pm 70\mu\text{V}$



Typical = $\pm\sigma = \pm 122\mu\text{V}$

Quiz: Statistics Behind Error Analysis

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